



PRODUCT BULLETIN
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ISSUE DATE: 23-Oct-2013
NOTIFICATION: 15857
TITLE: MC56F8014VFAE Test Site Expansion from ASE-ChungLi to Freescale TJN Final Mfg
EFFECTIVE DATE: 24-Oct-2013

DEVICE(S)

MPN
MC56F8014VFAE

AFFECTED CHANGE CATEGORIES

- TEST SITE

DESCRIPTION OF CHANGE

Freescale Semiconductor is announcing the test site transfer for MC56F8014VFAE from the current ASE-CL, ChungLi, Taiwan Final Test Facility to the Freescale TJN Final Mfg, Tianjin, China Final Test Facility.

REASON FOR CHANGE

Qualification of the Freescale Tianjin Final Mfg, Tianjin, China, Final Test Facility to improve manufacturing flexibility and customer support.

ANTICIPATED IMPACT OF PRODUCT CHANGE(FORM, FIT, FUNCTION, OR RELIABILITY)

There is no impact on device form, fit, function or reliability. The equivalent final test flows, hardware and software currently used in ASE-ChungLi, ChungLi, Taiwan Final Test facility will be implemented at the Freescale Tianjin Final Mfg, Tianjin, China Final Test facility.

NOTE:

THE CHANGE(S) SPECIFIED IN THIS NOTIFICATION WILL BE IMPLEMENTED ON THE EFFECTIVE DATE LISTED ABOVE. To request further data or inquire about the notification, please enter a [Service Request](#)

For sample inquiries - please go to www.freescale.com

QUAL DATA AVAILABILITY DATE: 30-Aug-2013

QUALIFICATION STATUS: COMPLETED

QUALIFICATION PLAN:

Freescale Semiconductor Manufacturing standard specification for test transfers was followed for the Test Transfer.

RELIABILITY DATA SUMMARY:

This device is fully qualified. No further Reliability data is needed for this change.

ELECTRICAL CHARACTERISTIC SUMMARY:

Parametric comparison between ASE-ChungLi, ChungLi, China and Freescale Tianjin Final Mfg, Tianjin, China was completed. Parameters show no significant difference.

CHANGED PART IDENTIFICATION:

There no change to the orderable part number.

ATTACHMENT(S):

External attachment(s) FOR this notification can be viewed AT:
[15857_Qualfication_Report-Test_Site_Expansion_56F8014V.pdf](#)
